# STL3NK40



# N-channel 400 V, 4.5 Ω typ., 0.43 A, SuperMESH™ Power MOSFET in a PowerFLAT™ 5x5 package

Datasheet - production data

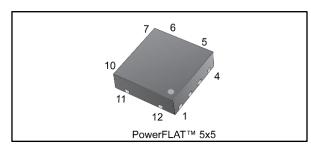
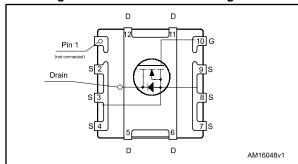


Figure 1: Internal schematic diagram



#### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ΙD	Ртот
STL3NK40	400 V	5.5 Ω	0.43 A	2.5 W

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized

### **Applications**

Switching applications

### **Description**

This high voltage device is an N-channel Power MOSFET developed using the SuperMESH™ technology by STMicroelectronics, an optimization of the well-established PowerMESH™. In addition to a significant reduction in on-resistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.

**Table 1: Device summary** 

Order code	Marking	Package	Packing	
STL3NK40	3NK40	PowerFLAT™ 5x5	Tape and reel	

Contents STL3NK40

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STL3NK40 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage	400	V
$V_{DGR}$	Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)	400	V
V <sub>G</sub> s	Gate-source voltage	± 20	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>pcb</sub> = 25 °C	0.43	Α
I <sub>D</sub> ('')	Drain current (continuous) at T <sub>pcb</sub> = 100 °C	0.27	Α
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	1.72	Α
P <sub>TOT</sub> <sup>(1)</sup>	Total dissipation at T <sub>pcb</sub> = 25 °C	lissipation at $T_{pcb} = 25  ^{\circ}\text{C}$ 2.5	
dv/dt (3)	Peak diode recovery voltage slope	4.5 V/r	
Tj	Operating junction temperature range	55 to 450	
T <sub>stg</sub>	Storage temperature range	- 55 to 150	°C

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-pcb</sub> <sup>(1)</sup>	Thermal resistance junction-pcb	50	°C/W

#### Notes:

**Table 4: Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or non-repetitive (pulse width limited by T <sub>jmax.</sub> )	0.43	А
Eas	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	60	mJ

 $<sup>\</sup>ensuremath{^{(1)}}\xspace$  When mounted on FR-4 board of 1 inch², 2 oz Cu (t < 100 s).

<sup>&</sup>lt;sup>(2)</sup>Pulse width limited by safe operating area.

 $<sup>^{(3)}</sup>I_{SD} \leq$  0.43 A, di/dt  $\leq$  200 A/µs; V<sub>DD</sub>< 320 V.

 $<sup>^{(1)}</sup>$ When mounted on 1 inch² FR-4 board, 2 oz Cu (t < 100 s).

Electrical characteristics STL3NK40

### 2 Electrical characteristics

 $T_C = 25$  °C unless otherwise specified

Table 5: On/off-state

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	400			V
		V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 400 V			1	μΑ
I <sub>DSS</sub>	Zero-gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}$ $T_{C} = 125 \text{ °C}^{(1)}$			50	μA
I <sub>GSS</sub>	Gate body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			±10	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 50 \mu A$	0.8	1.6	2	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 0.22 \text{ A}$		4.5	5.5	Ω

#### Notes:

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		ı	128	200	pF
Coss	Output capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0 \text{ V}$	ı	16	30	pF
Crss	Reverse transfer capacitance	V 00 = <b>V</b> V	ı	4	6	pF
Rg	Gate input resistance	f = 1 MHz gate  DC bias = 0 test signal level = 20 mV opendrain	1	12		pF
$Q_g$	Total gate charge	$V_{DD} = 320 \text{ V}, I_D = 1.4 \text{ A}$	-	8.7	13	nC
$Q_{gs}$	Gate-source charge	V <sub>GS</sub> = 0 to 10 V	-	0.9	-	nC
Q <sub>gd</sub>	Gate-drain charge	(see Figure 13: "Test circuit for gate charge behavior")	-	3.8	-	nC

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD}$ = 200 V, $I_{D}$ = 0.7 A,	-	3	ı	ns
t <sub>r</sub>	Rise time	$R_G = 4.7 \Omega$	-	4	-	ns
t <sub>d(off)</sub>	Turn-off delay time	V <sub>GS</sub> = 10 V (see <i>Figure 12: "Test</i>	-	18	-	ns
t <sub>f</sub>	Fall time	circuit for resistive load switching times" and Figure 17: "Switching time waveform")	-	16	•	ns

<sup>&</sup>lt;sup>(1)</sup>Defined by design, not subject to production test.

Table 8: Source-drain diode

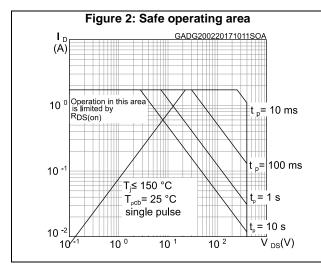
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		ı		0.43	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		1.72	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 0.43 A, V <sub>GS</sub> = 0 V	-		1.2	<b>V</b>
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 1.4 A, di/dt = 100 A/μs,V <sub>DD</sub> = 20 V (see Figure 14: "Test circuit for inductive load switching and diode	-	166		ns
Qrr	Reverse recovery charge		-	300		nC
I <sub>RRM</sub>	Reverse recovery current	recovery times")		3.6		Α
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 1.4 \text{ A}$ , $di/dt = 100 \text{ A/µs V}_{DD} = 20 \text{ V}$ , $T_j = 150 ^{\circ}\text{C}$ (see Figure 14: "Test circuit for inductive load switching and diode recovery times")		176		ns
Qrr	Reverse recovery charge			340		nC
I <sub>RRM</sub>	Reverse recovery current			3.8		Α

#### Notes:

 $<sup>\</sup>ensuremath{^{(1)}}\mbox{Pulse}$  width limited by safe operating area.

 $<sup>^{(2)}\</sup>text{Pulsed:}$  pulse duration = 300  $\mu\text{s,}$  duty cycle 1.5%.

### 2.1 Electrical characteristics (curves)



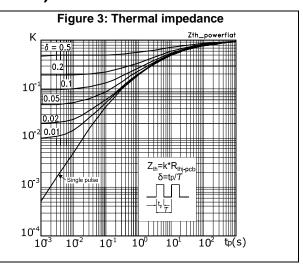
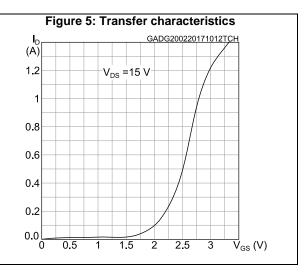
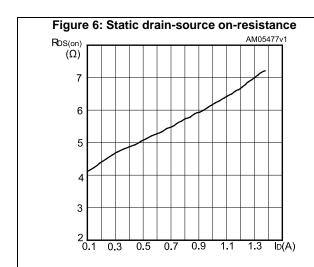
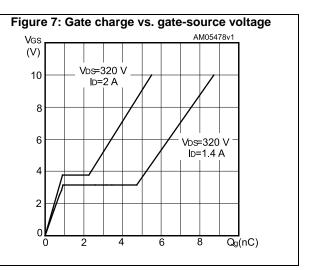


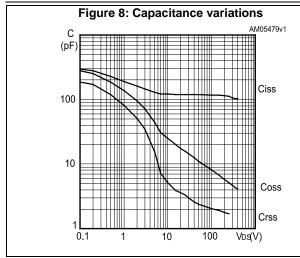
Figure 4: Output characteristics

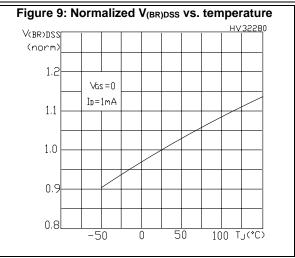
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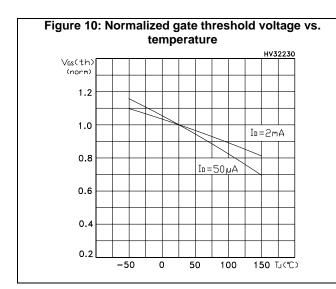


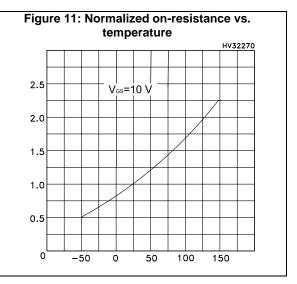












Test circuits STL3NK40

### 3 Test circuits

Figure 12: Test circuit for resistive load switching times

Figure 13: Test circuit for gate charge behavior

VGS

Pulse width

1 C CONST

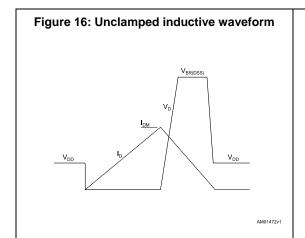
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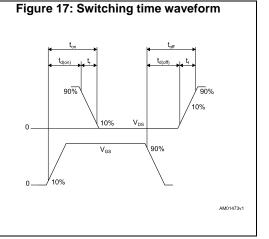
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Figure 14: Test circuit for inductive load switching and diode recovery times

Figure 15: Unclamped inductive load test circuit





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STL3NK40 Package information

# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.



# 4.1 PowerFLAT™ 5x5 package information

Figure 18: PowerFLAT™ 5x5 package outline

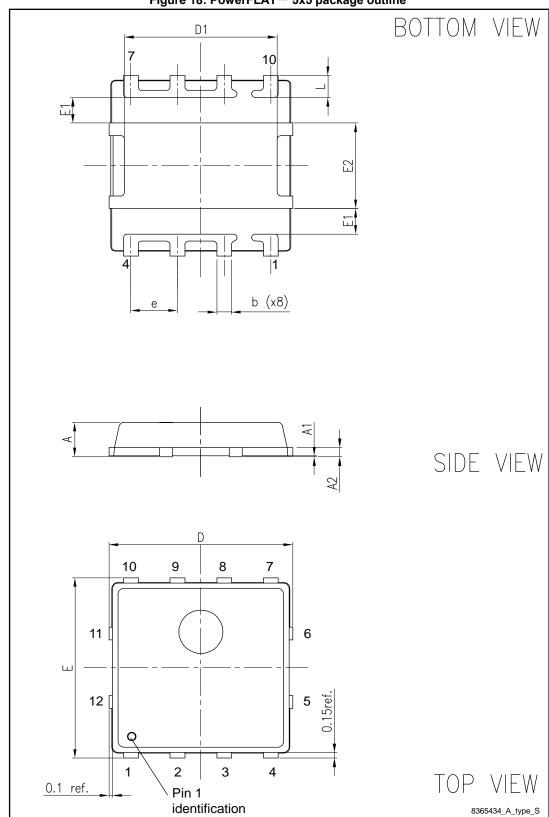
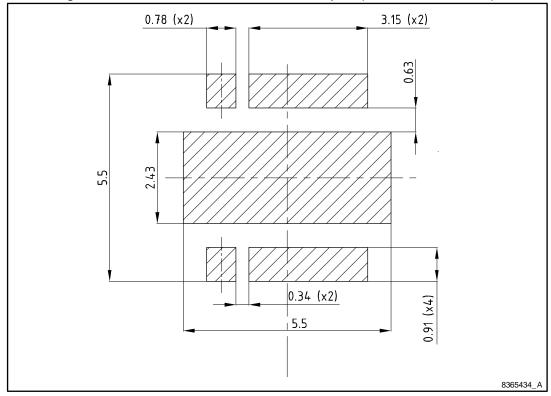


Table 9: PowerFLAT 5x5 package mechanical data

Dim.		mm	
Diiii.	Min.	Тур.	Max.
Α	0.80		1.0
A1	0.02		0.05
A2		0.25	
b	0.30		0.50
D		5.00	
D1	4.05		4.25
Е		5.00	
E1	0.64		0.79
E2	2.25		2.45
е		1.27	
L	0.45		0.75

Figure 19: PowerFLAT™ 5x5 recommended footprint (dimensions are in mm)



Revision history STL3NK40

# 5 Revision history

**Table 10: Document revision history** 

Date	Revision	Changes
18-Sep-2009	1	First release.
29-Aug-2013	2	Updated: Section 4: Package mechanical data Minor text changes
20-Feb-2017	3	Removed PowerFLAT™ 5x5 type C package information and cover image.  Updated <i>Table 6: "Dynamic"</i> and <i>Table 8: "Source-drain diode"</i> .  Updated <i>Section 2.1: "Electrical characteristics (curves)"</i> .  Minor text changes.

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